

Notice of References Cited	Application/Control No. 10/529,525		Applicant(s)/Patent Under Reexamination ONOZAWA, YASUhide	
	Examiner Long K. Tran		Art Unit 2818	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0164529	09-2003	Inoue et al.	257/414
*	B	US-6,543,109	04-2003	Taga, Shigeto	29/25.35
*	C	US-6,670,206	12-2003	Kim et al.	438/26
*	D	US-2004/0239449	12-2004	Stelzl et al.	333/187
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
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	T					

NON-PATENT DOCUMENTS

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